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# Cavity resonator method to measure the complex permittivity of low-loss dielectric plates

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The UK participation in its preparation was entrusted to Technical Committee EPL/46, Cables, wires and waveguides, radio frequency connectors and accessories for communication and signalling.

A list of organizations represented on this committee can be obtained on request to its secretary.

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ISBN 978 0 580 61106 3

ICS 172202033.12001

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 March 2011.

### Amendments issued since publication

Amd. No.	Date	Text affected
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EUROPEAN STANDARD

**EN 62562**

NORME EUROPÉENNE

EUROPÄISCHE NORM

February 2011

ICS 17.220

English version

**Cavity resonator method to measure the complex permittivity  
of low-loss dielectric plates**

(IEC 62562:2010)

Méthode de la cavité résonante pour  
mesurer la permittivité complexe des  
plaques diélectriques à faibles pertes  
(CEI 62562:2010)

Hohlraumresonanzverfahren zum Messen  
der komplexen Permittivität von  
verlustarmen dielektrischen Platten  
(IEC 62562:2010)

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**Management Centre: Avenue Marnix 17, B - 1000 Brussels**

## Foreword

The text of document 46F/118/CDV, future edition 1 of IEC 62562, prepared by SC 46F, R.F. and microwave passive components, of IEC TC 46, Cables, wires, waveguides, R.F. connectors, R.F. and microwave passive components and accessories, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62562 on 2011-01-02.

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- latest date by which the EN has to be implemented  
at national level by publication of an identical  
national standard or by endorsement (dop) 2011-10-02
- latest date by which the national standards conflicting  
with the EN have to be withdrawn (dow) 2014-01-02

## Endorsement notice

The text of the International Standard IEC 62562:2010 was approved by CENELEC as a European Standard without any modification.

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## CAVITY RESONATOR METHOD TO MEASURE THE COMPLEX PERMITTIVITY OF LOW-LOSS DIELECTRIC PLATES

### 1 Scope

The object of this International Standard is to describe a measurement method of dielectric properties in the planar direction of dielectric plate at microwave frequency. This method is called a cavity resonator method. It has been created in order to develop new materials and to design microwave active and passive devices for which standardization of measurement methods of material properties is more and more important.

This method has the following characteristics:

- the relative permittivity  $\epsilon'$  and loss tangent  $\tan\delta$  values of a dielectric plate sample can be measured accurately and non-destructively;
- temperature dependence of complex permittivity can be measured;
- the measurement accuracy is within 0,3 % for  $\epsilon'$  and within  $5 \times 10^{-6}$  for  $\tan\delta$  ;
- fringing effect is corrected using correction charts calculated on the basis of rigorous analysis.

This method is applicable for the measurements on the following condition:

- frequency :  $2 \text{ GHz} < f < 40 \text{ GHz}$ ;
- relative permittivity:  $2 < \epsilon' < 100$ ;
- loss tangent :  $10^{-6} < \tan\delta < 10^{-2}$ .

### 2 Measurement parameters

The measurement parameters are defined as follows:

$$\epsilon_r = \epsilon' - j\epsilon'' = D/(\epsilon_0 E) \quad (1)$$

$$\tan\delta = \epsilon''/\epsilon' \quad (2)$$

$$TC\epsilon = \frac{1}{\epsilon} \frac{d\epsilon}{dT} \times 10^6 \quad (1 \times 10^{-6}/K) \quad (3)$$

where

D is the electric flux density;

E is the electric field strength;

$\epsilon_0$  is the permittivity in a vacuum;

$\epsilon'$  and  $\epsilon''$  are the real and imaginary components of the complex relative permittivity  $\epsilon_r$ ;

$TC\epsilon$  is the temperature coefficient of relative permittivity;

$\epsilon$  and  $\epsilon_{ref}$  are the real parts of the complex relative permittivity at temperature T and

T

reference temperature  $T_{\text{ref}}$  (= 20 °C to 25 °C), respectively.



$$\left( \begin{array}{c} \pi t f \\ 0 \end{array} \right) \left( \begin{array}{c} \\ 2M \end{array} \right)$$

where  $c$  is the velocity of light in a vacuum ( $c = 2,997\,9 \times 10^8$  m/s) and the first root  $X$  is calculated from a given value  $Y$ , using the following simultaneous equations:

$$X \tan X = \frac{t}{2M} Y \cot Y \tag{5}$$

$$Y = \frac{\sqrt{k_0^2 - k_r^2}}{M k_r} = jY' \tag{6}$$

with  $k_0 = 2\pi f_0 c$ ,  $k_r = j'_{01} R$ , and  $j'_{01} = 3,83173$  for the  $TE_{011}$  mode. When  $k_0 - k_r < 0$ ,  $Y$  is replaced by  $jY'$ .

The value of  $\tan\delta_a$  is given by

$$\tan\delta_a = \frac{A}{Q_u - R_s B} \tag{7}$$

where  $R_s$  is the surface resistance of the conductor of cavity, given by

$$R_s = \frac{\pi f_0 \mu}{\sigma} \left( \frac{1}{S} \right), \quad \sigma = \sigma_0 \sigma_r \text{ (S/m)} \tag{8}$$

Here,  $\mu$  and  $\sigma$  are the permeability and conductivity of the conductor. Furthermore,  $\sigma_r$  is the relative conductivity and  $\sigma_0 = 5,8 \times 10^7$  S/m is the conductivity of standard copper. Constants  $A$  and  $B$  are given by

$$A = 1 + \frac{W_2^e}{W_1^e} \tag{9}$$

$$B = \frac{P_{cy1} + P_{cy2} + P_{end}}{\omega R_s W_1^e} \tag{10}$$

In the above,  $W_1^e$  and  $W_2^e$  are electric field energies stored in the dielectric plate of region 1 and air of region 2 shown in Figure 1a. Furthermore,  $P_{cy1}$ ,  $P_{cy2}$  and  $P_{end}$  are the conductor loss at the cylindrical wall in the region 1, 2 and at the end wall. These parameters are given by

$$W_1^e = \frac{\pi}{8} \frac{\epsilon_0 \epsilon_a \mu_0 \omega}{2} \frac{J_0^2(j'_{01})}{(j'_{01})^2} \frac{1}{1 + \frac{\sin 2X}{2X}} \tag{11}$$

$$W^e = \frac{\pi}{\epsilon \mu \omega} \frac{j_2 J_2}{2} \frac{j_1 J_1}{2} \frac{j_0 J_0}{2} \left( \frac{\sin 2Y}{\cos X} \right)^2 \quad (12)$$

$$\frac{2}{4} \frac{0}{0} \frac{01}{0} \frac{01}{0} \left( \frac{\sin 2Y}{2Y} \right)^2 Y$$

$$P_{cy} = \frac{\pi}{2} \frac{R J_1}{4} \frac{j_1 J_1}{tRk_1} \left( \frac{\sin 2X}{2X} \right)^2 \quad (13)$$

$$P_{cy2} = \frac{\pi}{R} \frac{j_1 J_1}{2} \frac{j_0 J_0}{s_0} \frac{j_2 J_2}{01} \frac{j_1 J_1}{r_4} \left( \frac{\sin 2Y}{\cos X} \right)^2 \quad (14)$$

$$P_{\text{end}} = \frac{\pi}{2} \frac{R_j^2 J_0^2(j'_{01})}{s_{01}^2} \left( \frac{Y}{\cos X} \right)^2 \frac{2}{\sin^2 Y} \left( \frac{M}{01} \right) \quad (15)$$

Then, accurate values of  $\epsilon'$  and  $\tan\delta$  are given by

$$\epsilon' = \epsilon' \frac{1 - \frac{\Delta A}{A}}{1 + \frac{\Delta B}{B}} \quad (16)$$

$$\tan\delta = \frac{A \left( \frac{\Delta A}{A} \right) + B \left( \frac{\Delta B}{B} \right)}{Q_u \left( 1 + \frac{\Delta A}{A} \right) - R_s \left( 1 + \frac{\Delta B}{B} \right)} \quad (17)$$

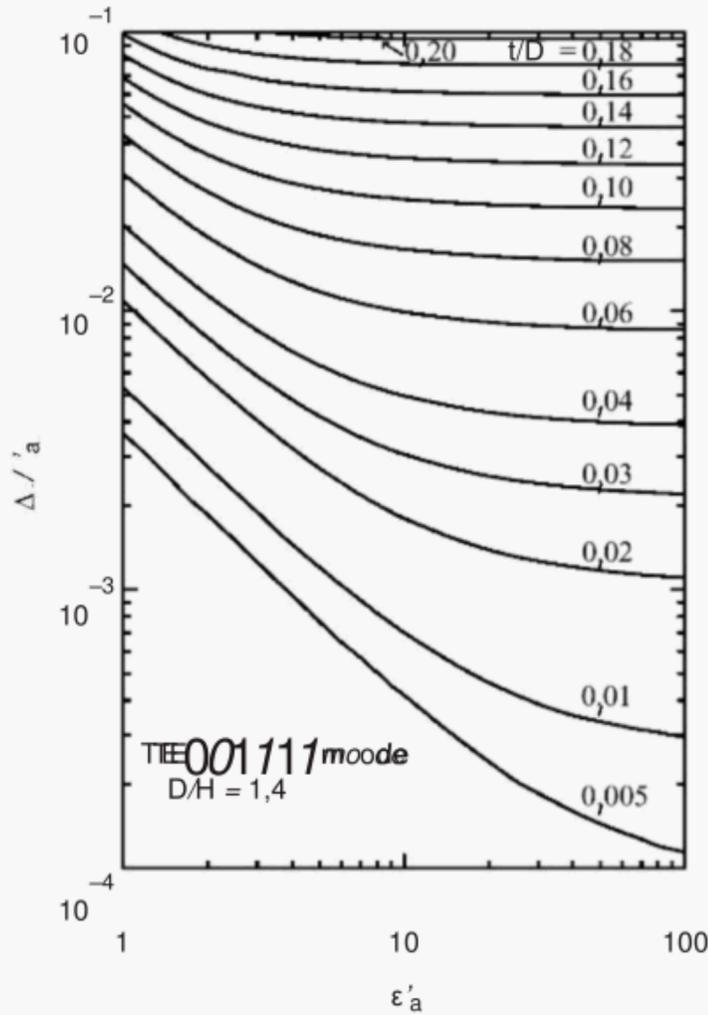
where correction terms due to the fringing field  $\Delta\epsilon' \epsilon'_a$ ,  $\Delta A$  A and  $\Delta B$  B are calculated numerically on the basis of rigorous mode matching analysis using the Ritz-Galerkin method, as shown in Figures 2 and 3. It is found from the analysis for a circular dielectric plate with diameter d that  $f_0$  converges to a constant value for  $d/D > 1,2$ . The correction terms shown in Figures 2 and 3 were calculated for  $d/D > 1,5$ . Therefore, the correction terms are applicable to dielectric plates with any shape if  $d/D > 1,2$ .

Measurement uncertainties of  $\epsilon'$  and  $\tan\delta$ ,  $\Delta\epsilon'$  and  $\Delta\tan\delta$  are estimated as the mean square errors and given respectively by

$$(\Delta\epsilon')^2 = (\Delta\epsilon_f)^2 + (\Delta\epsilon_t)^2 + (\Delta\epsilon_D)^2 + (\Delta\epsilon_H)^2 \quad (18)$$

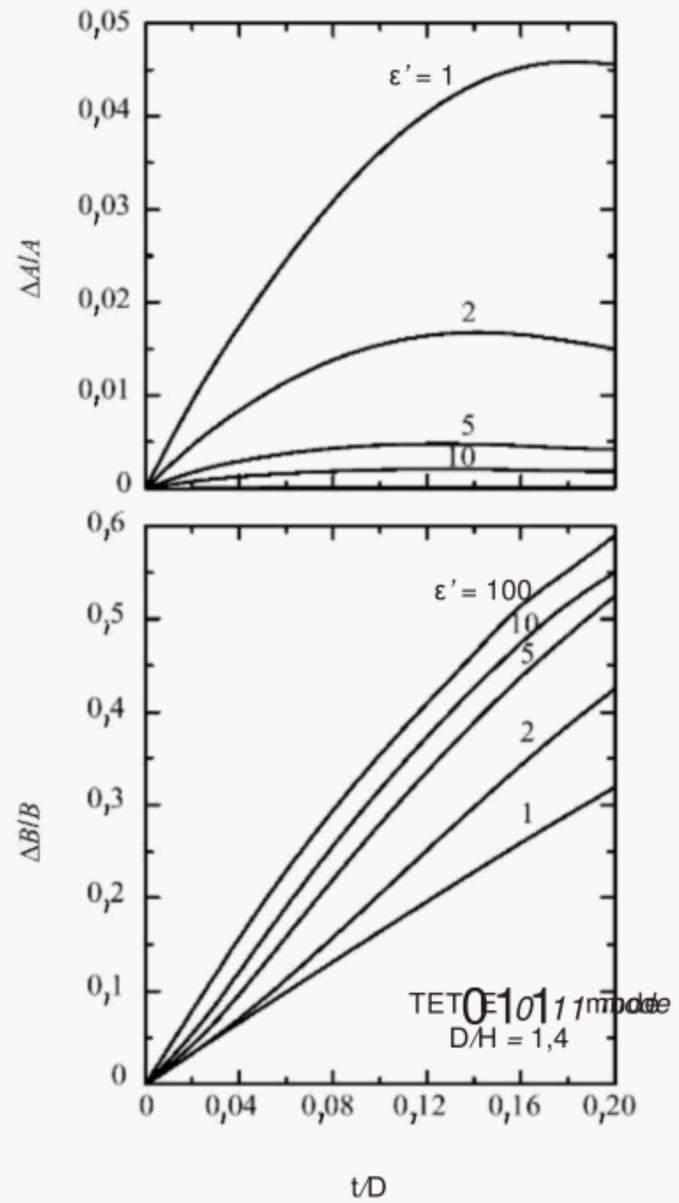
$$(\Delta\tan\delta)^2 = \Delta\delta_Q^2 + \Delta\delta_\sigma^2 \quad (19)$$

where  $\Delta\epsilon'_f$ ,  $\Delta\epsilon'_t$ ,  $\Delta\epsilon'_D$  and  $\Delta\epsilon'_H$  are the uncertainties of  $\epsilon'$  due to standard deviations of  $f_0$ ,  $t$ ,  $D$ , and  $H$ , respectively. Also,  $\Delta\tan\delta$  is mainly attributed to measurement errors of  $Q_u$  and  $\sigma_r$ , and  $\Delta\tan\delta_Q$  and  $\Delta\tan\delta_\sigma$  are uncertainties of  $\tan\delta$  due to standard deviations of them, respectively.



IEC 129/10

Figure 2 – Correction term  $\Delta\epsilon'/\epsilon'_a$



IEC 130/10

Figure 3 – Correction terms  $\Delta A/A$  and  $\Delta B/B$

### 3.2 Temperature dependence of $\epsilon'$ and $\tan\delta$

Temperature dependence of  $\epsilon'$  and  $\tan\delta$  also can be measured using this method. Temperature coefficient of relative permittivity  $TC\epsilon$  is calculated by equation (3).

When the temperature dependences of  $\epsilon'$  is linear, particularly,  $\epsilon'(T)$  is given by

$$\epsilon'(T) = \epsilon'(T_0)[1 + TC\epsilon(T - T_0)] \quad (20)$$

where  $T$  and  $T_0$  are the temperatures in measurement and the reference temperature, respectively. In this case,  $TC\epsilon$  can be determined by the least squares method for many measurement points against  $T$ .

The thermal linear expansion coefficient of the dielectric plate  $\alpha$  and that of the conductor cavity  $\alpha_c$  should be considered in the  $TC\epsilon$  measurement. Furthermore, the temperature coefficient of resistivity  $TC\rho$  should be considered in the temperature dependence measurement of  $\tan\delta$ . Using these parameters, temperature dependent values of  $t(T)$ ,  $D(T)$ ,  $H(T)$ , and  $\rho(T)$  are given by

$$t = \frac{t(T_0) + \alpha_c (T - T_0)}{1 + \alpha_c (T - T_0)} \quad (21)$$

$$D = \frac{D(T_0) + \alpha_c (T - T_0)}{1 + \alpha_c (T - T_0)} \quad (22)$$

$$H = \frac{H(T_0) + \alpha_c (T - T_0)}{1 + \alpha_c (T - T_0)} \quad (23)$$

$$\rho T = \frac{1}{\sigma T} = \frac{\rho T_0 + TC\rho (T - T_0)}{1 + TC\rho (T - T_0)} \quad (24)$$

### 3.3 Cavity parameters

Cavity parameters such as  $D$ ,  $H = 2M \sqrt{\alpha_c}$ ,  $\sigma_r$  and  $TC\rho$  are determined from the measurements for the  $TE_{011}$  and  $TE_{012}$  resonance modes of an empty cavity without a sample, in advance of complex permittivity measurements. At first,  $D$  and  $H$  are determined from two measured resonant frequencies,  $f_1$  for the  $TE_{011}$  mode and  $f_2$  for the  $TE_{012}$  mode, by using

$$D = \frac{c j'_{01}}{\pi} \sqrt{\frac{3}{4 f_1^2 - f_2^2}} \quad (25)$$

$$H = \frac{c}{2} \sqrt{\frac{3}{f_1^2 - f_2^2}} \quad (26)$$

which can be derived easily from the resonance condition of the cavity.

Secondly,  $\alpha_c$  is determined from the measurement of temperature dependence of  $f_1$ , by using

$$\alpha_c = \frac{1}{f_1} \frac{\Delta f}{\Delta T} \quad (27)$$

Thirdly,  $\sigma_r$  is determined from the measured values  $D$ ,  $H$ ,  $f_1$ ,  $Q_{uc}$ , which is the unloaded  $Q$ -factor for the  $TE_{011}$  mode, by the following equation:

$$4\pi f_1 Q_{uc} = \frac{1}{j} \left\{ \frac{D^2}{2} + \frac{H^2}{2\pi} \right\}$$

$$\sigma_r = \left( \begin{array}{c} \left( \frac{2H}{2} \right) \\ \left( \frac{\sigma \mu}{c} \right) \left( \frac{\pi D}{2} \right)^3 \\ + \left( \frac{0}{2} \right) \left( \frac{H}{2} \right) \end{array} \right) \quad (28)$$

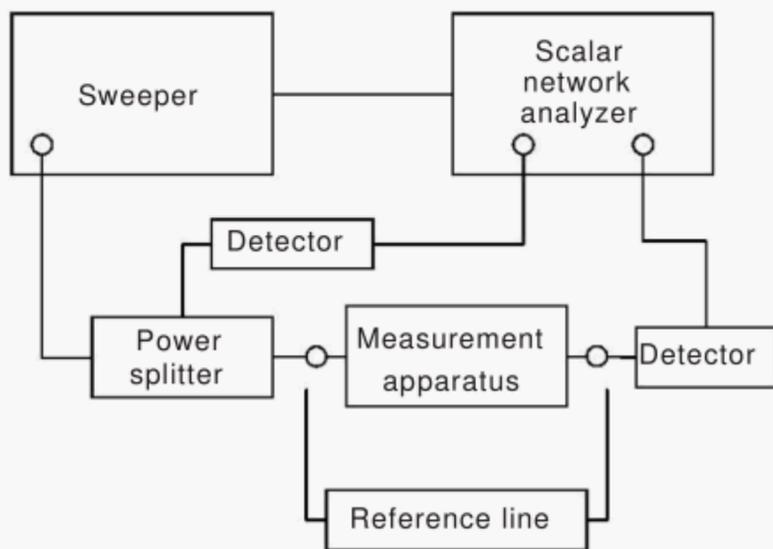
Finally, TCp is determined from the measurement of temperature dependence of  $\rho_r = \sigma_0 \sigma$  by using

$$TCp = \frac{1}{\rho_r} \frac{\Delta \rho_r}{\Delta T} \quad (29)$$

## 4 Measurement equipment and apparatus

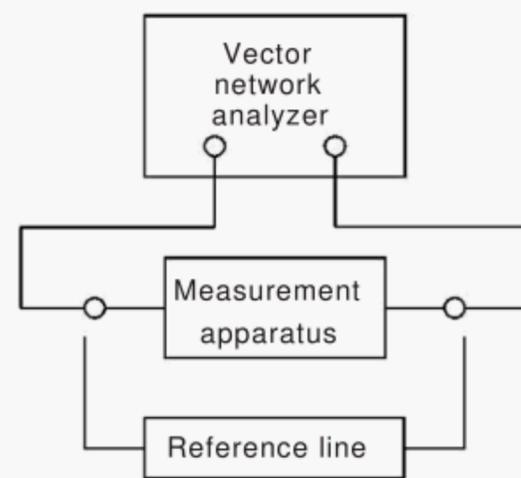
### 4.1 Measurement equipment

Figure 4 shows a schematic diagram of two equipment systems required for millimetre wave measurement. For the measurement of dielectric properties, only the information on the amplitude of transmitted power is needed, that is, the information on the phase of the transmitted power is not required. Therefore, a scalar network analyzer can be used for the measurement shown in Figure 4a. However, a vector network analyzer, as shown in Figure 4b, has an advantage in precision of the measurement data.



IEC 131/10

Figure 4a – Scalar network analyzer system



IEC 132/10

Figure 4b – Vector network analyzer system

Figure 4 – Schematic diagram of measurement equipments

### 4.2 Measurement apparatus for complex permittivity

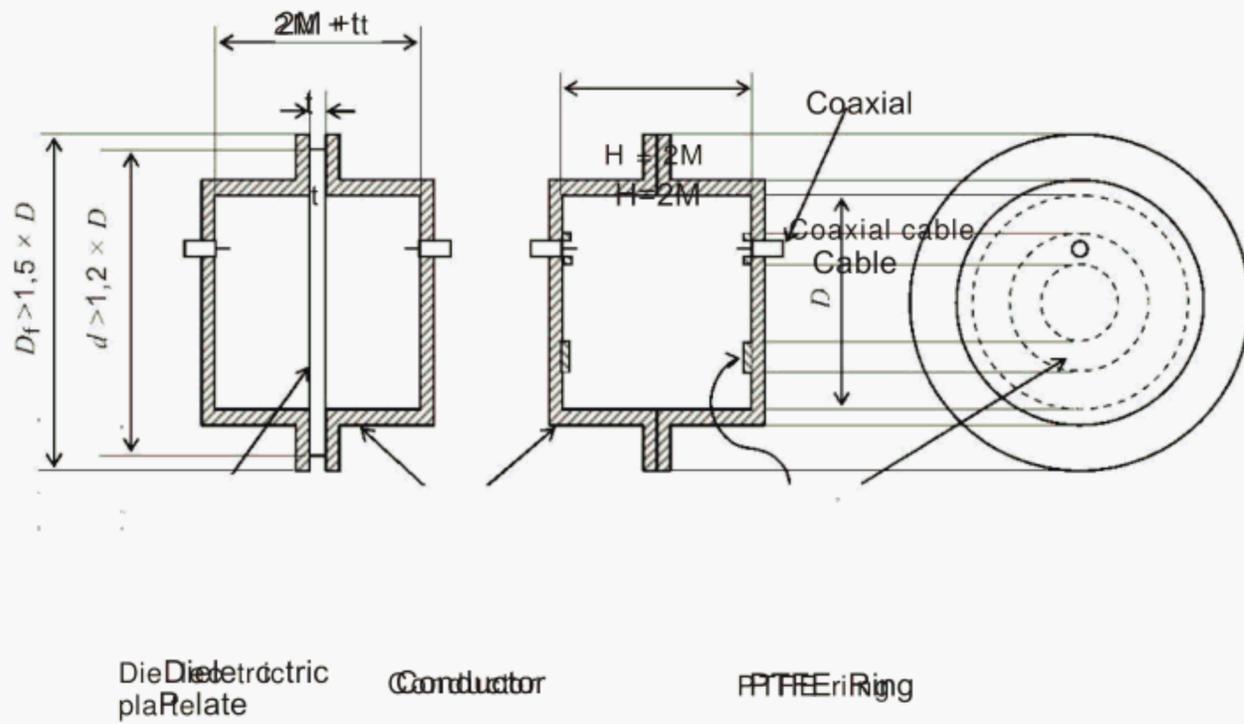
The structure of the cavity resonator used in the complex permittivity measurement is shown in Figure 5. A cylindrical cavity containing two cup-shaped parts is machined from a copper block. The cavity resonator has  $D = 35$  mm,  $H = 25$  mm and a flange diameter  $D_f > 1,5$  mm for the measurement around 10 GHz. A specimen with diameter  $d > 1,2 \times D$  is placed between the two parts and clamped with clips to fix this structure. This cavity resonator is excited by the two semi-rigid coaxial cables, each of which has a small loop at the top. The transmission-type resonator is constituted and under-coupled equally to the input and output loops with setting  $S_{11} = S_{22}$ . The photograph is shown in Figure 6.

The resonance frequency  $f_0$ , half-power band width  $f_{BW}$ , and the insertion attenuation  $IA_0$  (dB) at  $f_0$  are measured using a network analyzer by means of the swept-frequency method. The value of  $Q_u$  is given by

$$Q_u = \frac{Q}{L}, \quad Q = \frac{f_0}{L \cdot f} \tag{30}$$

$\frac{1}{-10} \frac{0}{-IA \text{ (dB)}/20}$

$BW$



Dielectric plate

Conductor

PTFE Ring

IEC 133/10

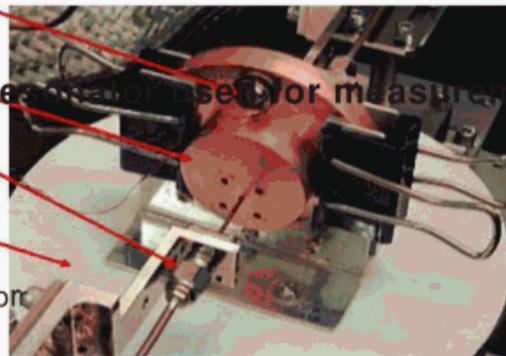
IEC 134/10

Figure 5a – Resonator clamping dielectric specimen

Figure 5b – Empty cavity resonator

Figure 5 – Cavity resonator used for measurement

Thermal sensor  
Thermal sensor  
Cavity resonator  
Coaxial cable  
Cold stage



IEC 135/10

Figure 6 – Photograph of cavity resonator for measurement around 10 GHz

## 5 Measurement procedure

### 5.1 Preparation of measurement apparatus

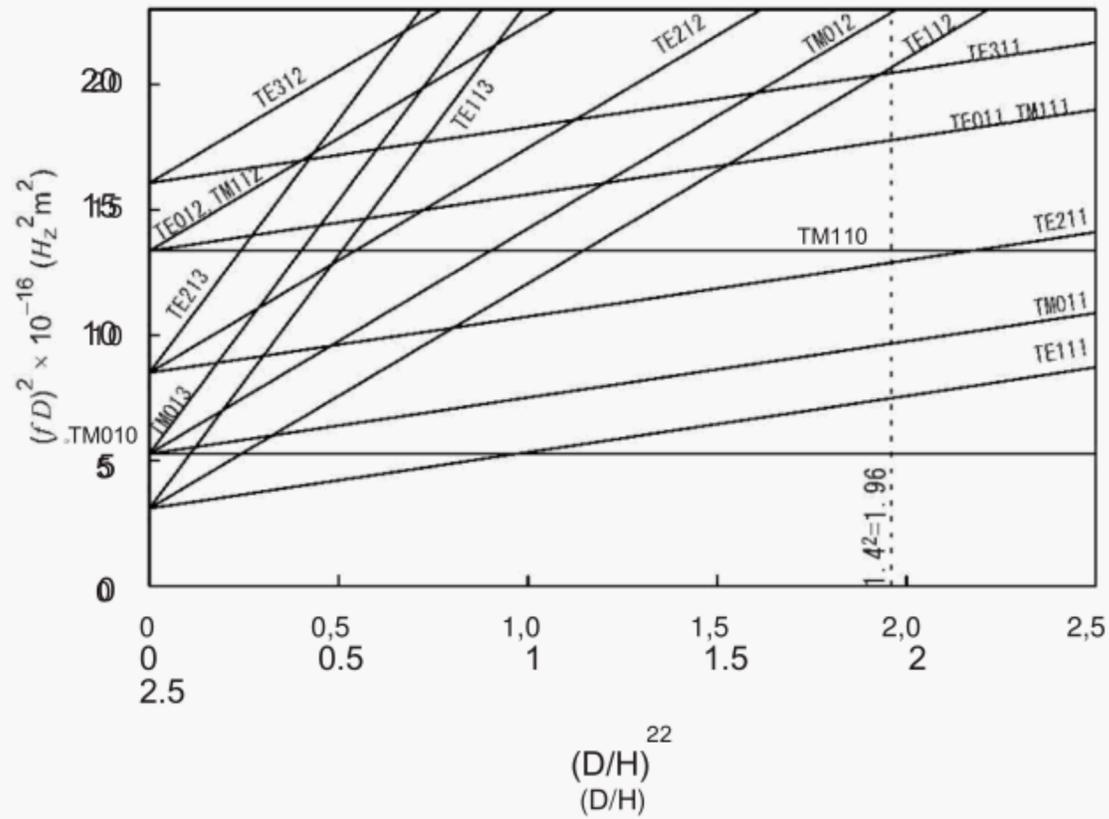
Set up the measurement equipment and apparatus as shown in Figure 4. The cavity resonator and dielectric specimens shall be kept in a clean and dry state, as high humidity degrades unloaded Q. The relative humidity shall preferably be less than 60 %.

### 5.2 Measurement of reference level

The reference level, level of full transmission power, is measured first. Connect the reference line to the measurement equipment and measure the full transmission power level over the entire measurement frequency range.

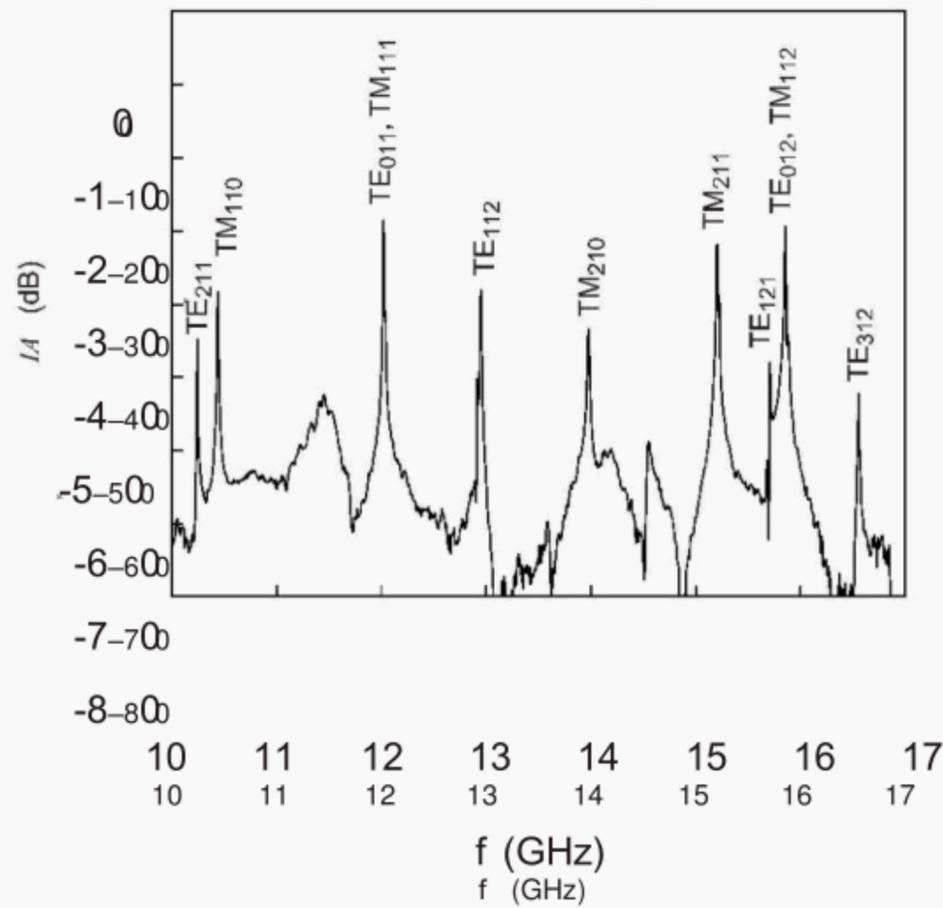
### 5.3 Measurement of cavity parameters: $D$ , $H$ , $\sigma_r$ , $\alpha_c$ , $TC_p$

Rough values of  $f_1$  of the  $TE_{011}$  resonance mode and  $f_2$  of the  $TE_{012}$  resonance modes can be estimated from the mode chart shown in Figure 7. Resonance peaks of cavity resonator with  $D = 35$  mm and  $H = 25$  mm are shown in Figure 8.



IEC 136/10

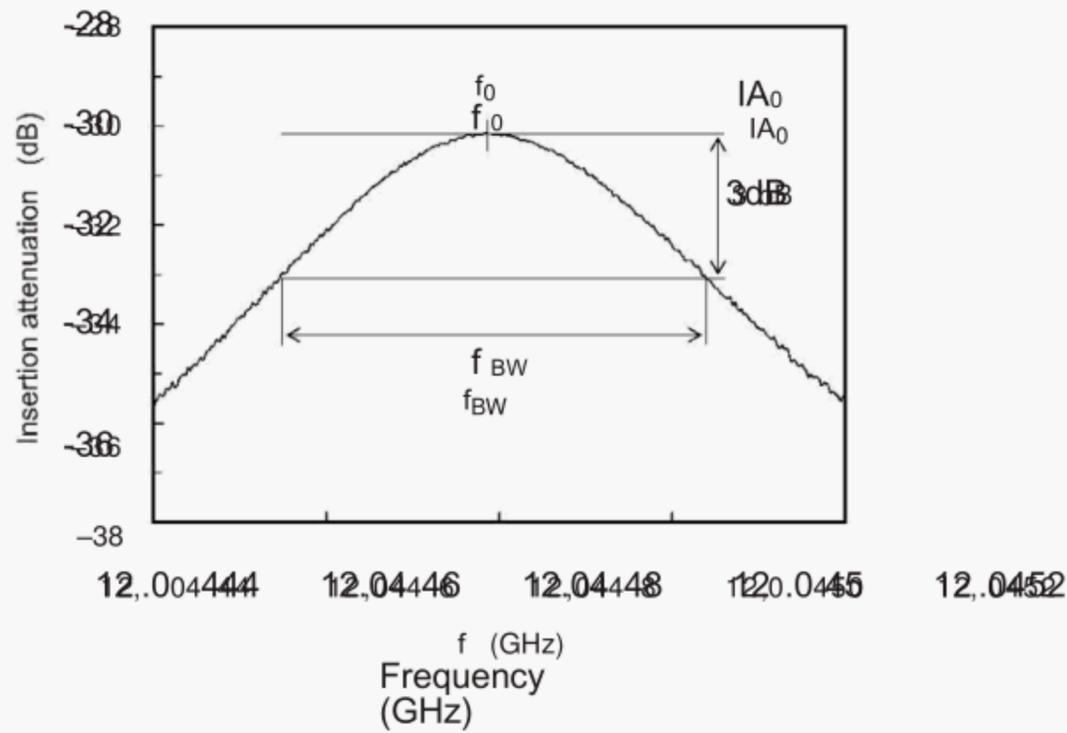
Figure 7 – Mode chart of cavity resonator



IEC 137/10

Figure 8 – Resonance peaks of cavity resonator

Attach PTFE rings to the end plates of the cavity to separate the degenerate  $TM_{11\ell}$  ( $\ell=1, 2$ ) modes from the  $TE_{01\ell}$  modes, as shown in Figure 5. Set the empty cavity and adjust the insertion attenuation  $IA_0$  to be around 30 dB by changing the distance between two semi-rigid cables, as shown in Figure 9.



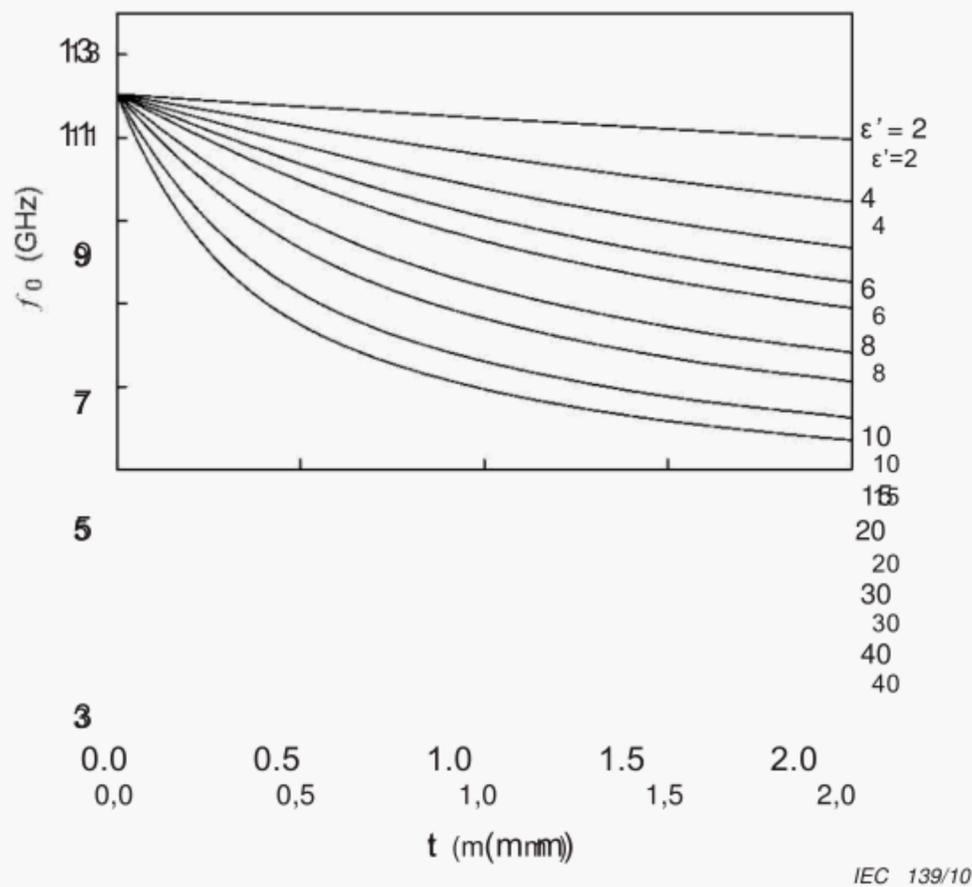
IEC 138/10

**Figure 9 – Resonance frequency  $f_0$ , insertion attenuation  $IA_0$  and half-power band width  $f_{BW}$**

Measure  $f_1$  and  $Q_{UC}$  of the  $TE_{011}$  resonance mode and measure  $f_2$  of the  $TE_{012}$  resonance modes. Calculate  $Q_{U1}$  by using equation (30). Calculate the dimensions  $D$ ,  $H$ , and  $\sigma_r$  of cavity resonator from equations (25), (26) and (28). Since the value of  $\sigma_r$  degrades due to oxidation of the metal surface, it shall be measured periodically. Next, measure temperature dependence of  $f_1$  and  $Q_{UC}$  using the cavity placed in a temperature-stabilized oven. Calculate  $\alpha_c$  and  $TC\rho$  from equations (27) and (29).

#### 5.4 Measurement of complex permittivity of test specimen: $\epsilon'$ , $\tan\delta$

Place the test specimen between two cylinders and clamp them by clips, as shown in Figure 6. Estimate a rough value of  $f_0$  of the  $TE_{011}$  resonance mode from Figure 10. Then, measure  $f_0$  and  $Q_u$  values. Calculate  $\epsilon'$  and  $\tan\delta$  values using equations (4) to (17).



**Figure 10 – Resonance frequency  $f_0$  of TE<sub>011</sub> mode of cavity resonator with dielectric plate (D = 35 mm, H = 25 mm)**

### 5.5 Temperature dependence of $\epsilon'$ and $\tan\delta$

Place a cavity resonator clamping the dielectric plate in a temperature-stabilized oven, and measure  $f_0$  and  $Q_u$  as a function of temperature  $T$ . Calculate  $\epsilon'$  and  $\tan\delta$  values as a function of  $T$ , taking account of  $\alpha$ ,  $\alpha_c$ , and  $TC\rho$ . Then, calculate  $TC\epsilon$  by using equation (3) or by the least squares method for many measurement points against  $T$ .

## Annex A (informative)

### Example of measured result and accuracy

#### A.1 Cavity parameters

Table A.1 shows measured results of cavity parameters. As shown in this table, D and H can be determined accurately to  $\mu\text{m}$  order using  $f_1$  and  $f_2$ . The value of  $\sigma_r$  depends on the surface roughness and the oxidation of the internal wall of the cavity and is desired to be higher than 80 % to keep high accuracy in the  $\tan\delta$  measurement.

**Table A.1 – Measured results of cavity parameters**

$f_1$ (GHz) for TE <sub>011</sub>	$f_2$ (GHz) for TE <sub>012</sub>	$Q_u$ for TE <sub>011</sub>	D mm	H mm	$\alpha_c$ ppm/K	$\sigma_r$ %	TCp 1/K
12,045 6	15,936	24 256	35,053	24,884	15,5	84,4	0,003 4
$\pm 0,000 2$	$\pm 0,001$	$\pm 145$	$\pm 0,001$	$\pm 0,002$	$\pm 0,3$	$\pm 1,0$	$\pm 0,000 3$

Measured results of temperature dependence of  $f_1$  and  $Q_{uc}$  for an empty cavity resonator are shown in Figure A.1. The value of  $\alpha_c$  in Table A.1 was determined from the temperature dependence of  $f_1$  using equation (27). Furthermore, TCp was determined from the temperature dependence of  $Q_{uc}$  using equation (29). In these calculations,  $\Delta f_1/\Delta T$  and  $\Delta p_r/\Delta T$  were determined by the least squares method. The values of  $\alpha_c$  are nearly equal with nominal value of 16,5 ppm/K<sup>1)</sup> of copper. The values of TCp are around the nominal value TCp = 0,003 9 (1/K) of copper at DC.

1) ppm = parts per million

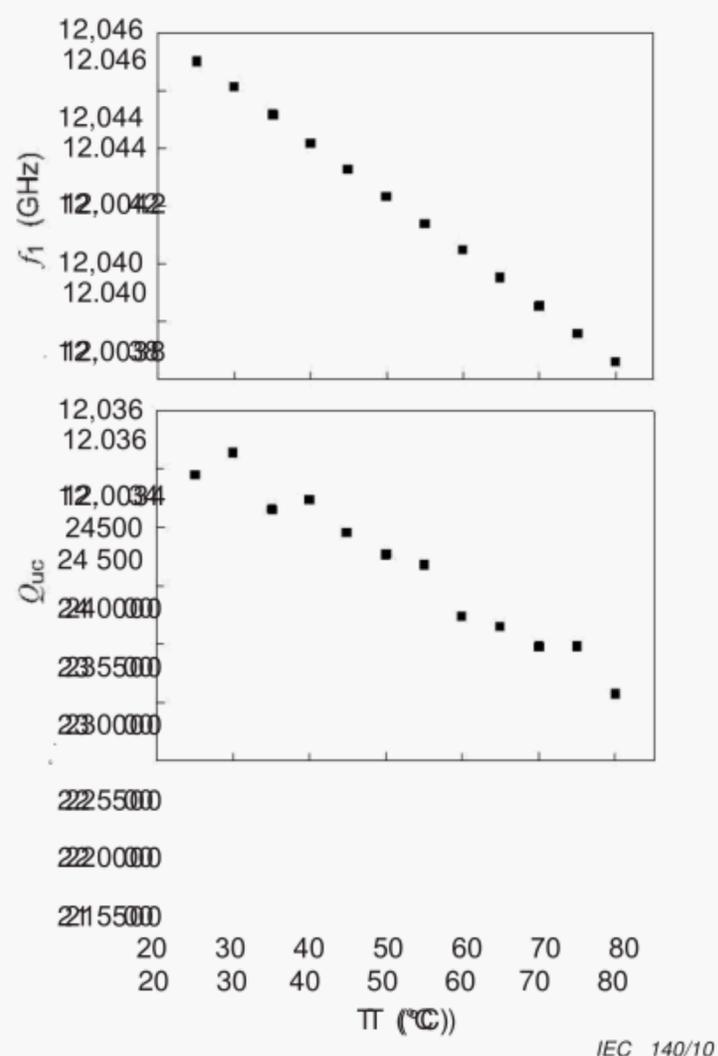
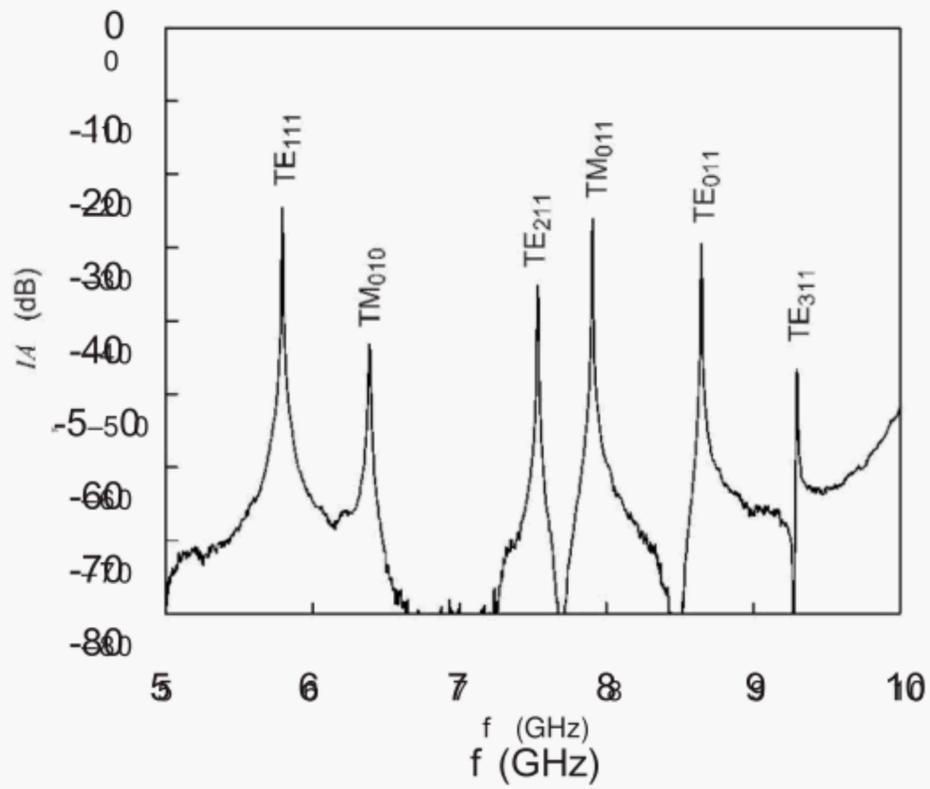


Figure A.1 – Measured temperature dependence of  $f_1$  and  $Q_{uc}$

## A.2 Relative permittivity $\epsilon'$ and $\tan\delta$

Figure A.2 shows measured resonance peaks of cavity resonator clamping sapphire plate and Table A.2 shows measured values of  $\epsilon'$  and  $\tan\delta$  for the sapphire plate with  $t = 0,958 \pm 0,002$  mm at room temperature. The values of  $\epsilon'$  are the perpendicular component of relative permittivity against c-axis. Measurement errors  $\Delta\epsilon'$  and  $\Delta\tan\delta$  were calculated by using equations (18) and (19). A main cause of  $\Delta\epsilon'$  is uncertainty of the sample thickness.



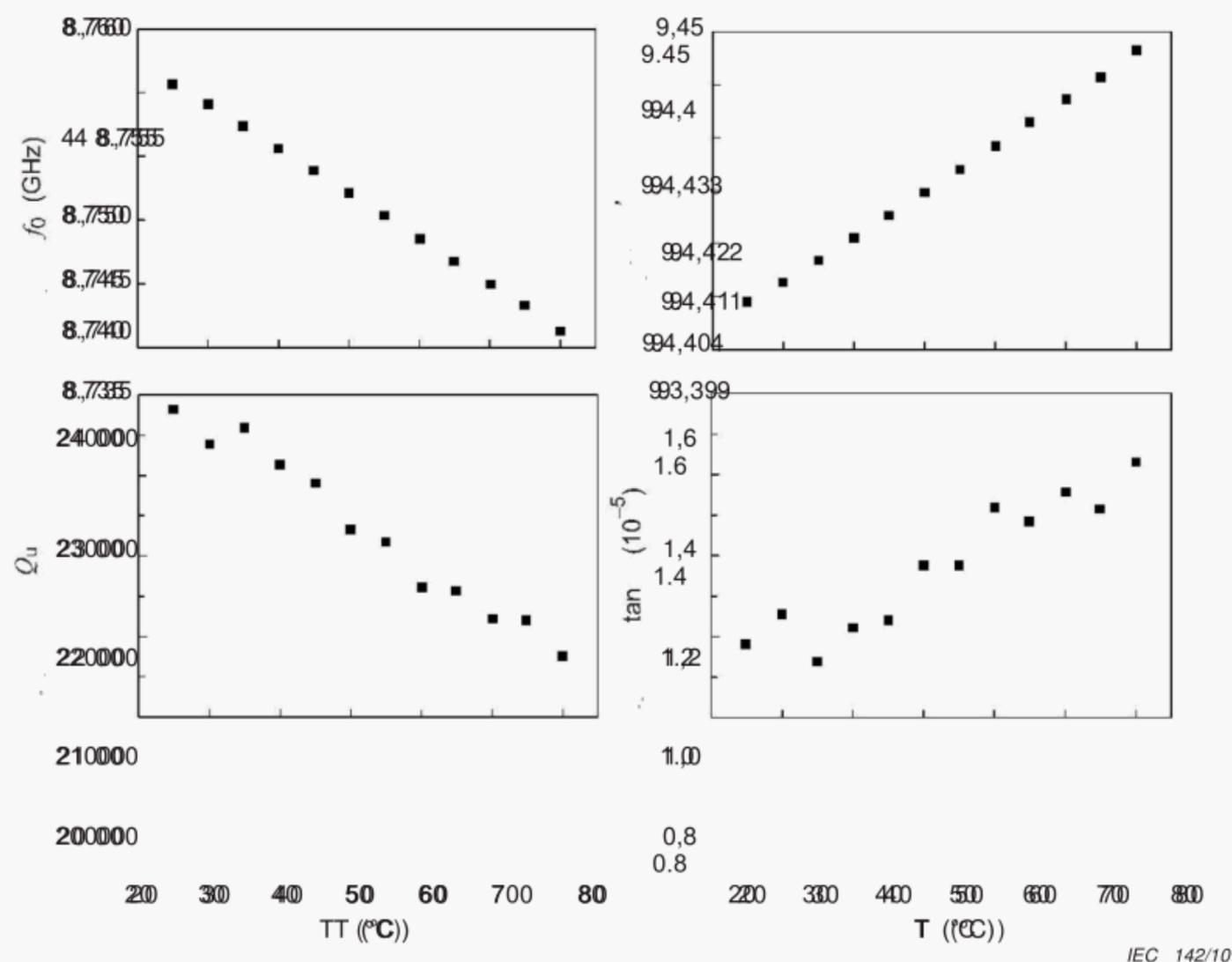
IEC 141/10

Figure A.2 – Resonance peaks of cavity resonator clamping sapphire plate

Table A.2 – Measured results of  $\epsilon'$  and  $\tan\delta$  for sapphire plate

$f_0$ (GHz)	$Q_u$	$\epsilon'$	$\tan\delta$ ( $10^{-5}$ )	$\sigma_r$ (%)
8,754 6	24 043	9,404	0,91	84,4
$\pm 0,000 1$	$\pm 165$	$\pm 0,017$	$\pm 0,06$	$\pm 1,0$

Figure A.3 shows measured results of temperature dependence of  $f_0$ ,  $Q_u$ ,  $\epsilon'$  and  $\tan\delta$  for the sapphire plate. The value of  $\epsilon'$  decreases linearly and  $\tan\delta$  increases approximately linearly, with increasing T. Value of  $TC\epsilon$  was determined to be 92 ppm/K using by the least squares method from  $\epsilon'$  values against T.



**Figure A.3 – Measured results of temperature dependence of  $f_0$ ,  $Q_u$ ,  $\epsilon'$  and  $\tan \delta$  for sapphire plate**

### A.3 Measurement accuracy

By a round robin test [3]2) for the cavity resonance method, the accuracy of this method was estimated to be within 0,3 % for  $\epsilon'$ , within 4 % for  $\tan \delta$  of  $10^{-4}$  and 20 % for that of  $10^{-6}$ . The measurement resolution of  $TC\epsilon$  is estimated to be 1 ppm/K for  $TC\epsilon$  of  $-10$  ppm/K, and to be 3 ppm/K for  $TC\epsilon$  of 90 ppm/K. This high measurement accuracy and resolution are acceptable for most practical applications for microwave planar circuits.

2) Figures in square brackets refer to the Bibliography.

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